Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/681,659	AERTGEERTS ET AL.	
	Examiner	Art Unit	
	Nashaat T. Nashed, Ph. D.	SEQ	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
SEQ ID NO: 3 and 1 (residues 27-760) search for interference		8/23/2007	NASH

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST Search, enclosed.	8/30/2007	NASH